Poster Session





Development of 5G Electrical Contact for use in Test, Burn-In, & Tri-Temp

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Plastronics saw a need to develop an H-Pin product that meet the following criteria:

- 1. Signal Speeds greater the 30 GHz at -1db
- 2. A test height of 1 mm or less
- 3. Pitch of 0.4 mm
- An impedance of 50 Ohms 4.
- Contact resistance of 35 milliohms or less initially

The following are the designs used to meet those criteria

BGA Version

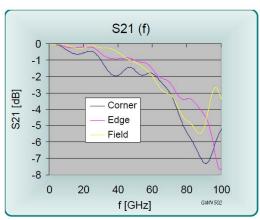




LGA Version

To insure good electrical performance, contacts were place at a 450 to each other to increase distance between pins which would also improve electrical performance.

Data from Gatewave

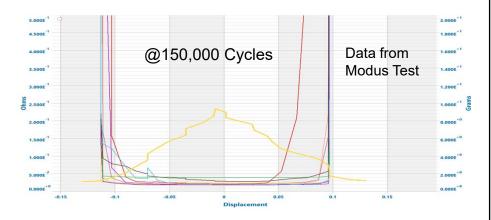


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Measurement results:

Data from Gatewave Northern

| | Comer | Edge | Field | |
|---------------------------|-------|------|-------|-----|
| Delay | 7.6 | 6.3 | 6.6 | ps |
| Risetime open | 28.5 | 28.5 | 28.5 | ps |
| Risetime short | 34.5 | 30 | 79.5 | ps |
| Risetime thru, 50Ω | 15 | 13.5 | 13.5 | ps |
| | | | | |
| Insertion loss (1dB) | 30.5 | 50.1 | 47.4 | GHz |
| Insertion loss (3dB) | 70.8 | 74.1 | 68.6 | GHz |
| VSWR (2:1) | 83.9 | >100 | 50.1 | GHz |



Summary:

- 1. We tested at 50.1 for field pins at -1db
- 2. Test height at 1.0 mm
- 3. Pitch as tested at 0.4 mm with pins on 45 angle
- 4. Measured impedance of 54.9 Ohms
- 5. Measured initial resistance at 28 milliohms

CRITERIA MET!!

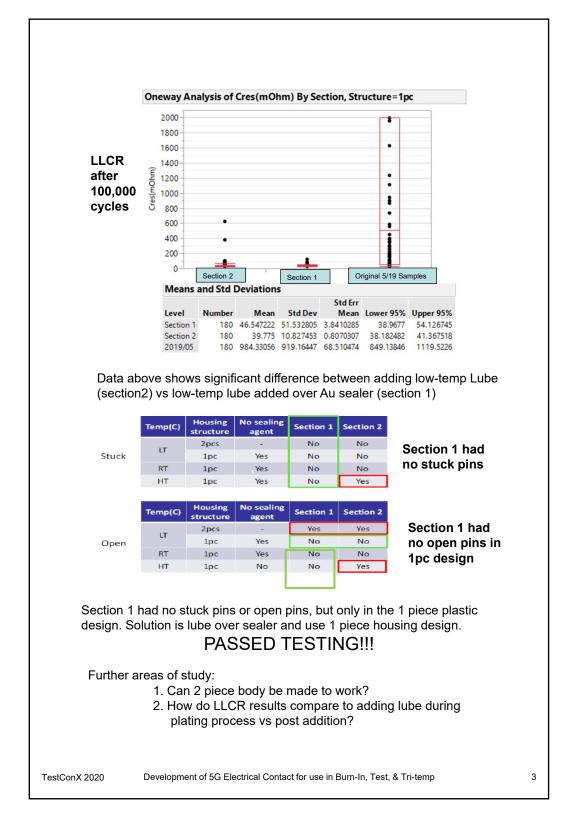
Next Objective: To pass tri-temp testing at three temperatures of 125C, 26C, and -55C at 100,000 cycles. LLCR is used as criteria for Pass/Fail. Initial results dated 05/2019 had a large deviation. Added lubricant to cleaned parts (section 2) and added same lubricant over a Au sealer (section 1). We also considered a 1 vs 2 piece plastic housing design in the same tests.

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